Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/050,123	YEN ET AL.
Examiner	Art Unit
Jason M. Perilla	2638

SEARCHED					
Class	Subclass	Date	Examiner		
375	295	9/29/2005	JP		
	146	9/29/2005	JP		
	296	9/29/2005	JP		
	297	9/29/2005	JP		
710	8	9/29/2005	JP		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH (INCLUDING SEAR	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
East USPAT/USPGPUB EPO/JPO	9/29/2005	JP	
Inventor Name Search	9/29/2005	JP	
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